Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/647,163	LOU ET AL.
Examiner	Art Unit
Hanh Nguyen	2616

	SEARCHED				
Class	Subclass	Date	Examiner		
370	203	12/10/07	HN		
	210				
	208				
	342				
	320				
	328				
	441				
	274				
	202				
	212				
370	215				
375	241				
	262				
375	240.28				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1			

SEAI (INCLUDING S	RCH NOTI)
		DATE	EXMR
East		12/10/2007	HN